

CHANGE IN CONTACT RESISTANCE BY DURABILITY TEST

Probe tip shape : Round< $\phi 1$ >

Spring Force : 150g

Base material of DUT : Copper

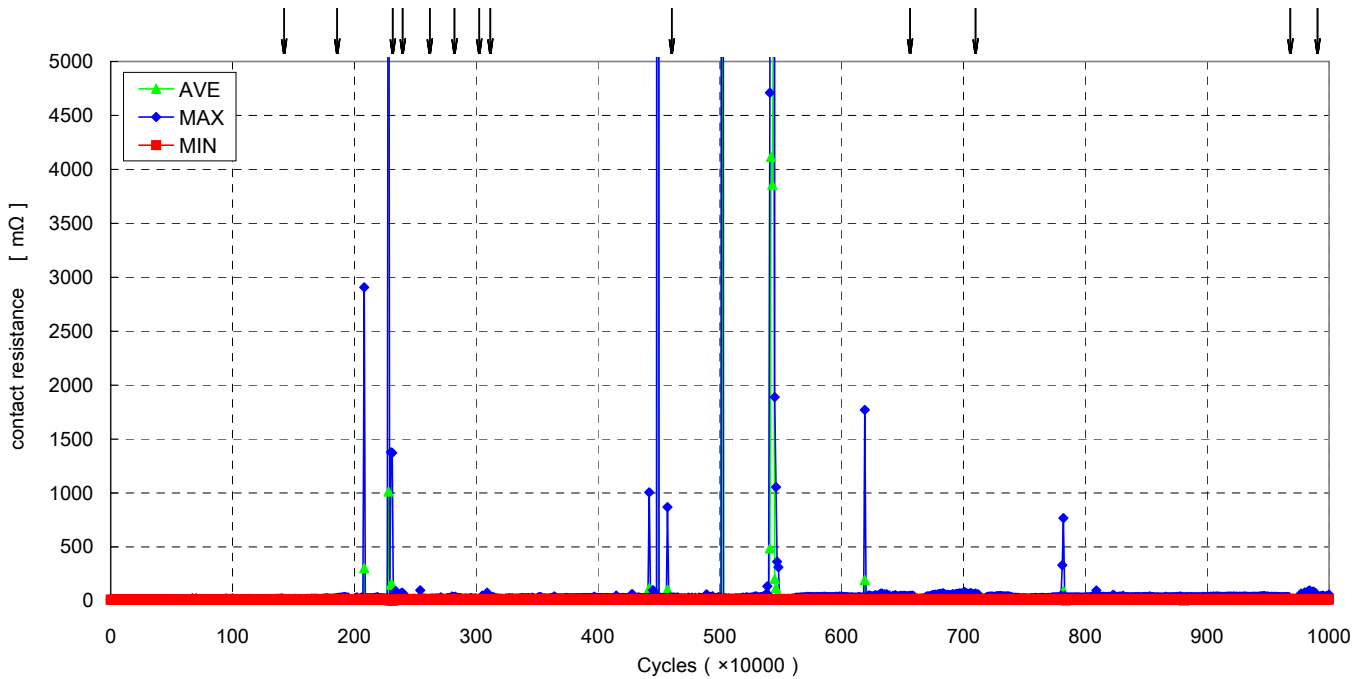
Surface of DUT : Aurum plating

Wire connection : wiring with terminal

1. Outer spring type contact probe (Sankei Engineering's products)

Values include intrinsic resistance of a probe, a terminal and a device under test (DUT).

Mark ↓ : probe tip cleaning (wiping with a cloth dipped in ethanol)



2. Inner spring type contact probe

Values include intrinsic resistance of a probe, a terminal and a device under test (DUT).

Mark ↓ : probe tip cleaning (wiping with a cloth dipped in ethanol)

